

MT3004

N-Channel Enhancement Mode Field Effect Transistor

Product Summary

- $V_{DS} = 30V$
- $I_D = 80A$
- $R_{DS(ON)} = 3.5m\Omega @V_{GS}=10V$
- $R_{DS(ON)} = 5.0m\Omega @V_{GS}=4.5V$

Features

- Advanced Trench Process Technology.
- High Density Cell Design for Ultra Low
- On-Resistance.
- Lead free product is acquired.
- RoHS Compliant.

Applications

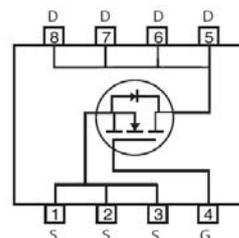
- Notebook Computer
- Portable Battery Pack



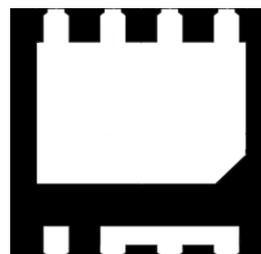
MT Semiconductor®

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Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



DFN3X3-8L

PIN1

Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted					
Parameter	Symbol	Maximum	Units		
Drain-Source Voltage	V_{DS}	30	V		
Gate-Source Voltage	V_{GS}	± 20	V		
Continuous Drain Current ^{AF}	I_{DSM}	$T_A=25^{\circ}C$	80		
		$T_A=70^{\circ}C$	65		
Pulsed Drain Current ^B	I_{DM}	160	A		
Avalanche Current ^C	I_{AR}	42	A		
Repetitive avalanche energy $L=0.3mH^C$	E_{AR}	75	mJ		
Power Dissipation	P_{DSM}	$T_A=25^{\circ}C$	2.8		
		$T_A=70^{\circ}C$	1.6		
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^{\circ}C$		
Thermal Characteristics					
Parameter	Symbol	Typ	Max	Units	
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	$t \leq 10s$	32	40	$^{\circ}C/W$
Maximum Junction-to-Ambient ^A		Steady-State	60	75	$^{\circ}C/W$
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	16	24	$^{\circ}C/W$	

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}$, $V_{GS}=0\text{V}$			1	μA
					100	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	0.8	1.5	2.0	V
$I_{D(ON)}$	On state drain current	$V_{GS}=10\text{V}$, $V_{DS}=5\text{V}$	100			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}$, $I_D=15\text{A}$		3.5	4.5	m Ω
		$V_{GS}=4.5\text{V}$, $I_D=15\text{A}$		5.0	7.8	m Ω
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}$, $I_D=20\text{A}$		68		S
V_{SD}	Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_S=40\text{A}$		0.7	1.3	V
I_S	Maximum Body-Diode + Schottky Continuous Current				50	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=15\text{V}$, $f=1\text{MHz}$		1920	2260	pF
C_{oss}	Output Capacitance			750		pF
C_{rss}	Reverse Transfer Capacitance			68		pF
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$		0.8	1.2	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}$, $V_{DS}=15\text{V}$, $I_D=20\text{A}$		29	35	nC
$Q_g(4.5\text{V})$	Total Gate Charge			14	16	nC
Q_{gs}	Gate Source Charge			4.6		nC
Q_{gd}	Gate Drain Charge			4.6		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=10\text{V}$, $V_{DS}=15\text{V}$, $R_L=1.2\Omega$, $R_{GEN}=3\Omega$		5.5		ns
t_r	Turn-On Rise Time			5.5		ns
$t_{D(off)}$	Turn-Off DelayTime			25		ns
t_f	Turn-Off Fall Time			4.3		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}$, $di/dt=500\text{A}/\mu\text{s}$		15	17	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}$, $di/dt=500\text{A}/\mu\text{s}$		32	38	nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=150^\circ\text{C}$.

C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

F: The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

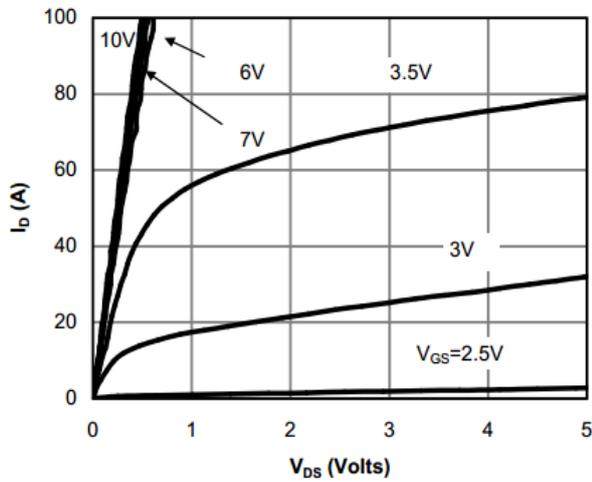


Fig 1: On-Region Characteristics (Note E)

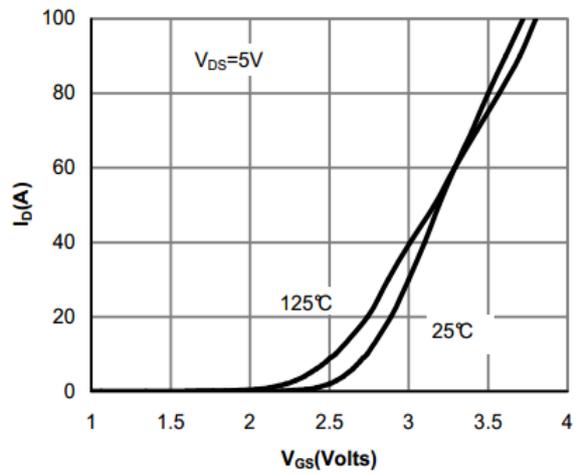


Figure 2: Transfer Characteristics (Note E)

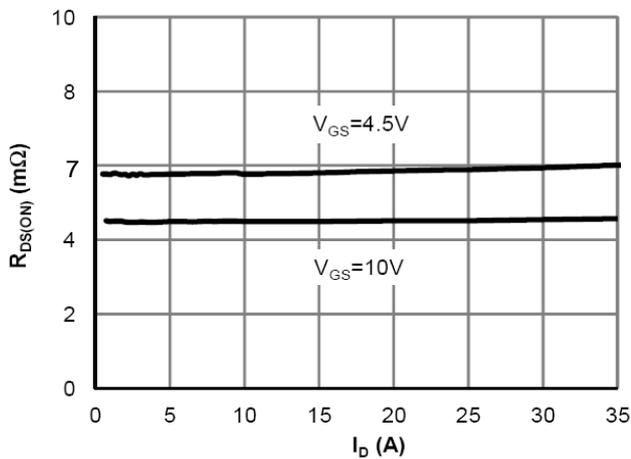


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

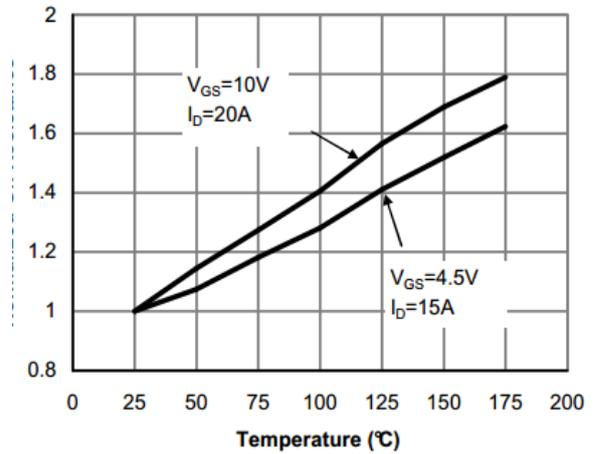


Figure 4: On-Resistance vs. Junction Temperature (Note E)

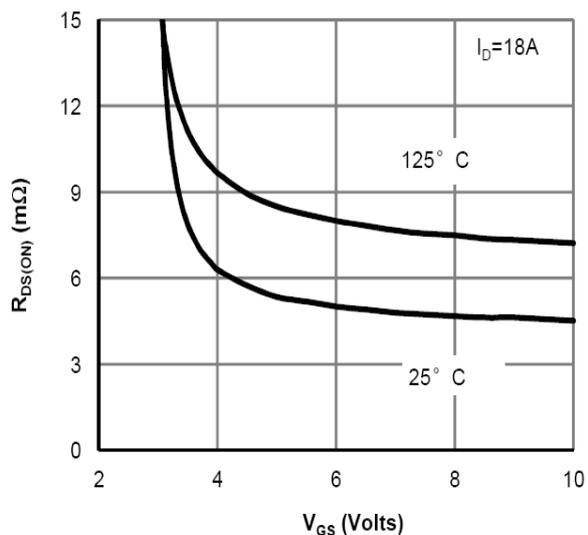


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

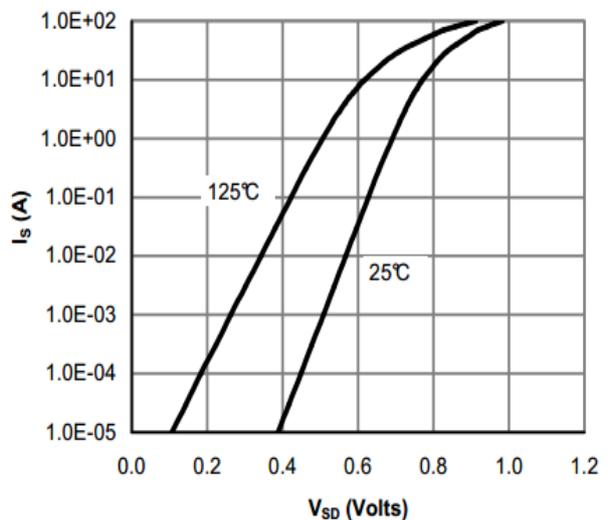


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

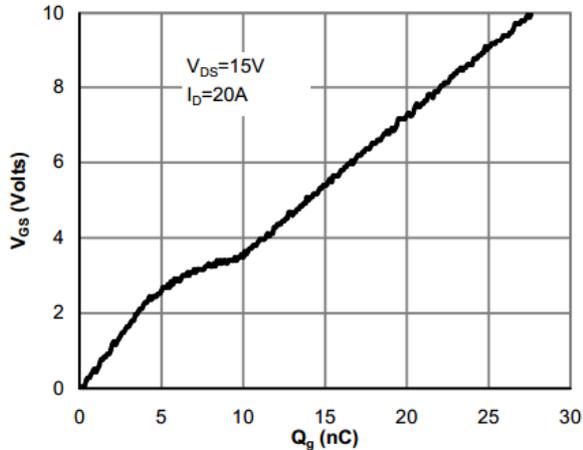


Figure 7: Gate-Charge Characteristics

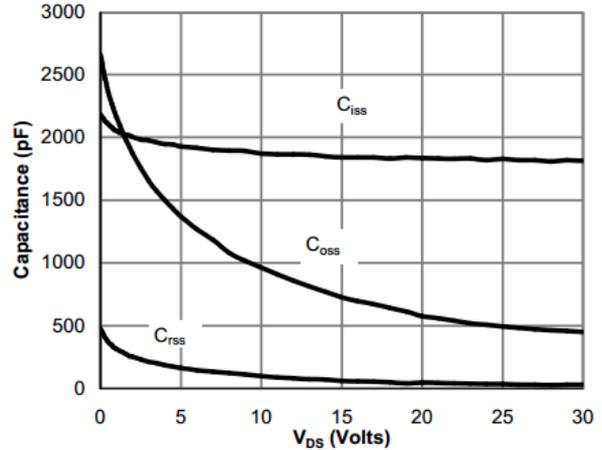


Figure 8: Capacitance Characteristics

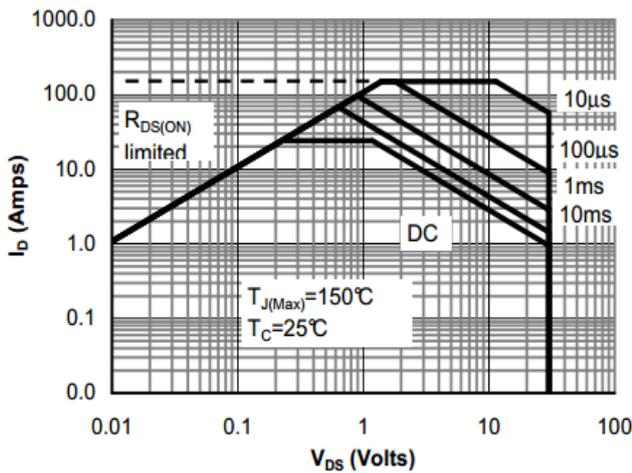


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

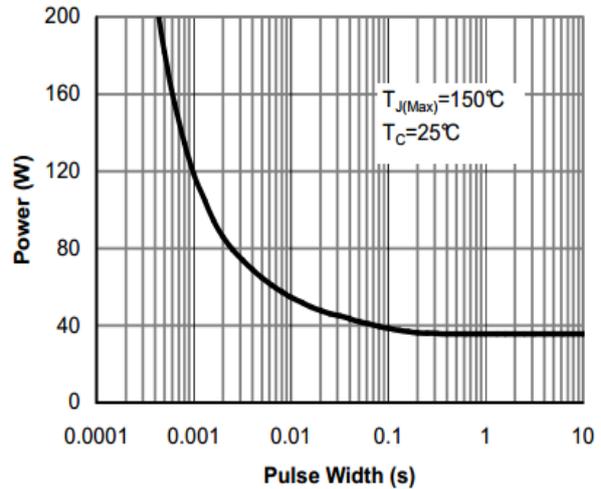


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

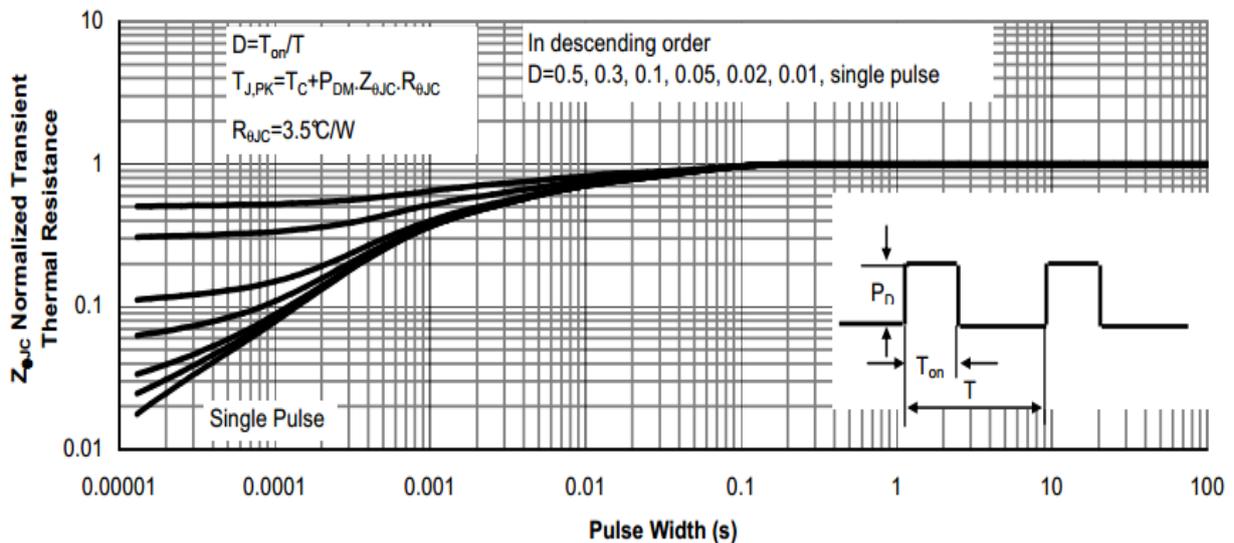
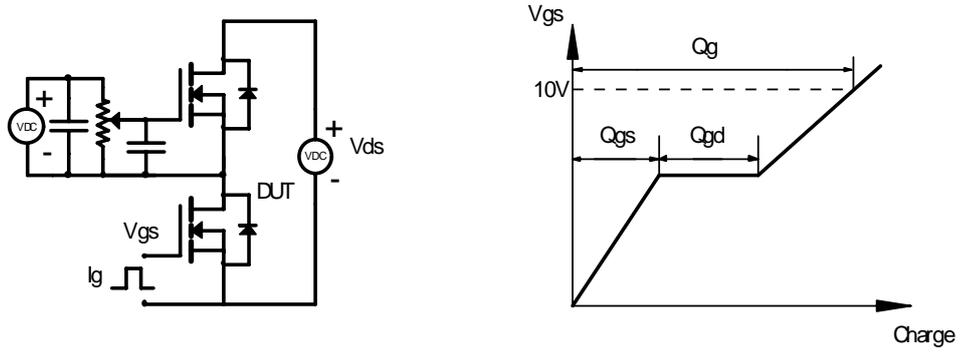
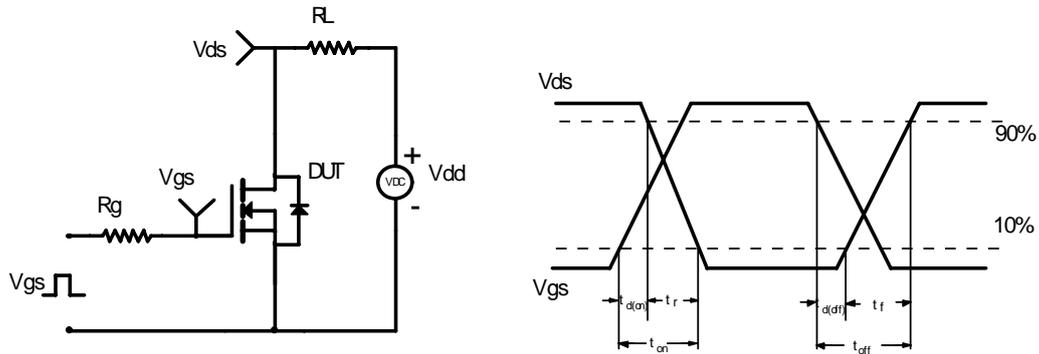


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

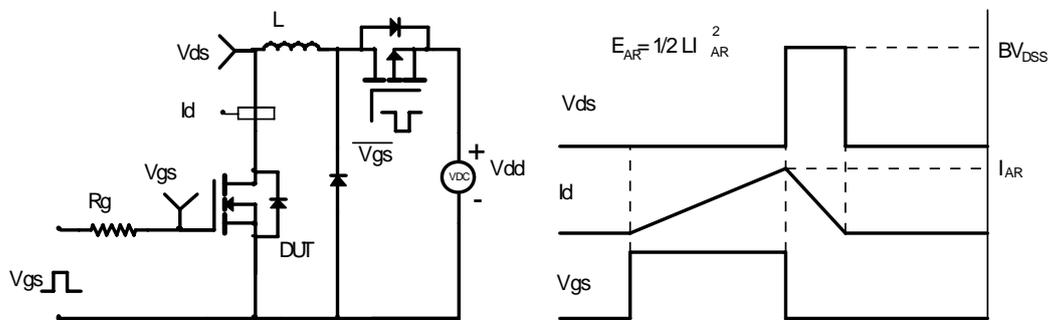
Gate Charge Test Circuit & Waveform



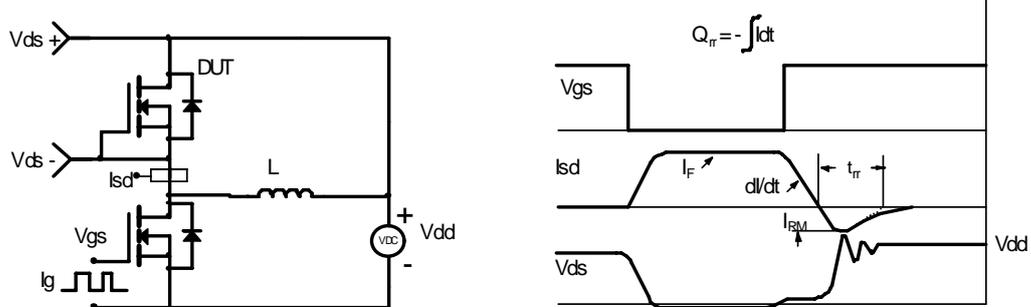
Resistive Switching Test Circuit & Waveforms



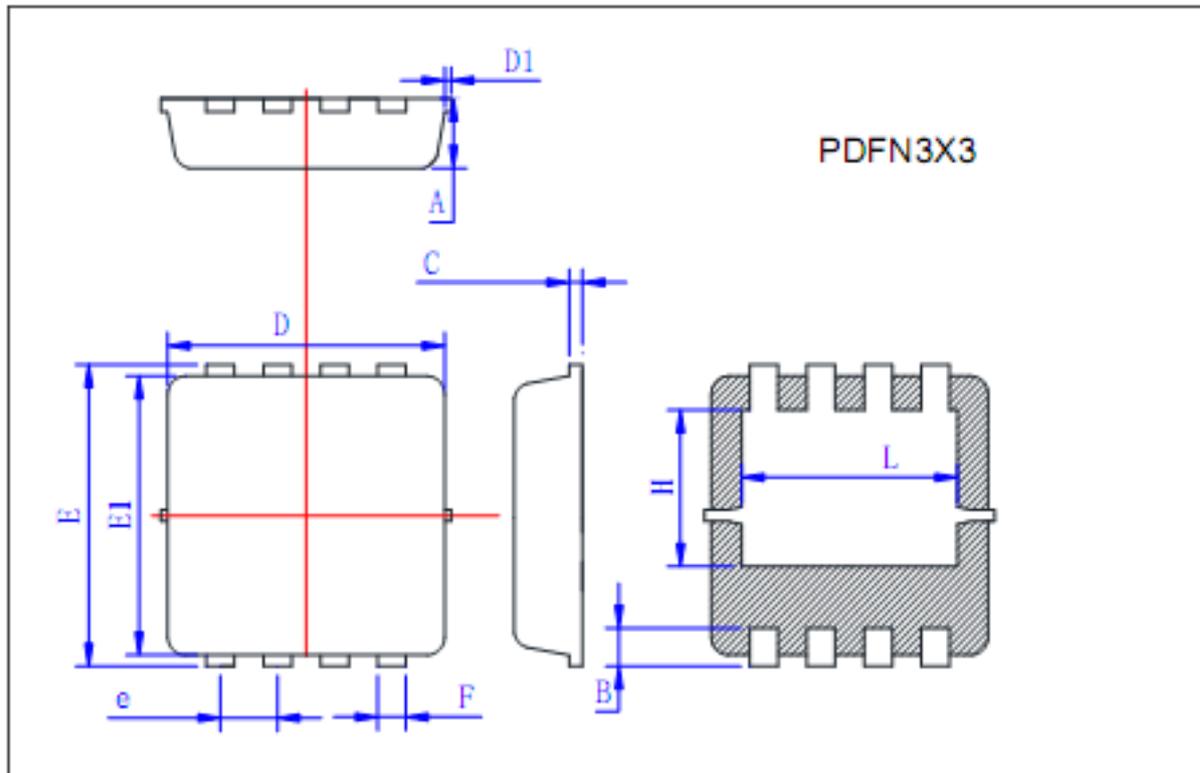
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



PACKAGE OUTLINE DIMENSIONS



Symbol	Min	Typ	Max
A	0.725	0.775	0.825
B	0.28	0.38	0.48
C	0.13	0.15	0.20
D	3.05	3.15	3.25
D1			0.10
E	3.25	3.35	3.45
E1	3.0	3.1	3.2
e	0.60	0.65	0.70
F	0.27	0.32	0.37
H	1.63	1.73	1.83
L	2.35	2.45	2.55

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